



Frithjof Nolting :: Head of LSC :: Paul Scherrer Institut

Status PSI CB&TP

SFA-AM review meeting 17./18. March 2022



Imaging and Diffraction Platform for Advanced Manufacturing and Industrial Processing

In this project, we upgrade the characterization capabilities for advanced manufacturing in particular at the Neutron, the Synchrotron and the Muon facility at PSI, but also for additional characterization.

Investment in new technology platforms

- The focus is to improve the performance of existing beamlines by developing new or enhancing existing detectors and improving the sample environment (MS, microXAS,
- Fully open to users (via proposal system)

Financing of key staff to operate and maintain the technology platforms

- Personal for engineering work, imaging and diffraction data analysis and for support of industrial related activities in advanced manufacturing.
- Support of users, method developments and industry projects

Co-financing of new professorships

Joint group between PSI and EPFL

In the following some examples will be presented

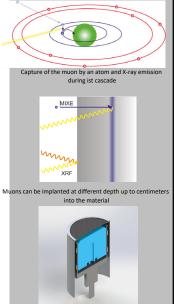


Depth-dependent elemental analysis with negative muons

Demand for non-destructive elemental analysis

The MIXE (Muon-Induced X-ray Emission), using negative muons is a rapidly evolving technique

- Muons can implanted deeply into a material at a tunable depth
- The X-rays created during the cascade of the muon into its ground state have high energy and can escape from the material
- The MIXE technique is sensitive to all elements
- Possibility to determine the elemental composition of operando devices (f.ex. batteries) or costly samples
- Set-up developed at PSI
- Biswas, S. et al., Appl. Sci. 2022, 12, 2541. https://doi.org/10.3390/app12052541





Investment Muon beamline detector



- Muon Induced X-ray Emission (MIXE)
 - Non-destructive elemental analysis
 - Sensitive to nearly all elements
 - Complementary to other techniques
 - bulk (10μm-mm) depth profiling
- PSI best institute to perform MIXE
 - Most intense continuous muon source
- · Applied to e.g.
- Precious objects like Archeological artifacts
- Extraterrestrial objects
- Layered structures e.g. Li-batteries
- Detection of MIXE signals by High Purity Germanium Detectors (HPGe)

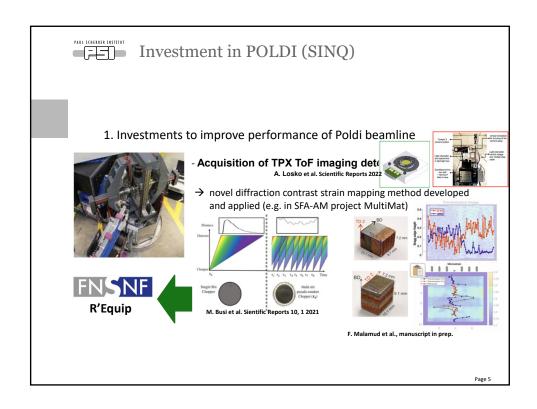


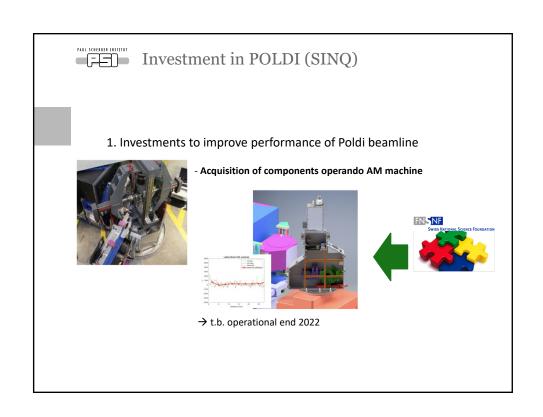




Please contact us if you are interested in this technique https://www.psi.ch/en/smus/muon-induced-x-ray-emission-mixe-project

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Investment upgrade Material Science beamline (SLS)

Horizontal mirror: to improve focusing and operability

- · Design completed
- · Parts ordered
- Installation by the end of the year, including movement of DCM and vertical mirrors

Eiger 500 K: improved detector for 3D station

• Installed and commissioned since Feb 22

Hexapod: replacement, improving speed

· Currently evaluating offers





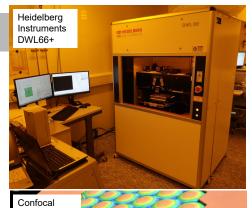
microscopy:

 $\begin{array}{l} \text{microlenses} \\ (\text{Ø 20 } \mu\text{m}^2, \end{array}$

photoresist)

in 16 µm thick

Microscope for quality control of 3D structures



New direct laser writer at PSI

is well suited for flexible patterning of 3D structures for research and industrial projects (ANAXAM)

- 3D diffraction gratings and microlenses
- microfluidics and mechanics

In comparison to electron beam lithography laser lithography is faster and enables patterning larger areas at industrial scales.

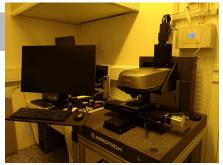
A confocal microscope enables

- Precise measurement of 3D contours
- Establishment of novel 3D processes for additive manufacturing
- Closes the optimization loop for the laser writer

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Microscope for quality control of 3D structures



10.000

Width (µm)

100.000 150.000 200.000

Laser Scanning Confocal Microscope

Keyence VK-X 3100 with 404 nm laser with Aerotech 300x300 mm² stage for

- · fast visualization of 3D topographies with high resolutions down to 250 nm
- large area automated scanning
- roughness measurement

Applications

5.000 0.000 0.000

- 3D quality control for new laser writer
- micro-optics from smartphones to X-ray applications (SLS)
- microfluidics for biosensors

50.000

defect analysis in 3D manufacturing

https://www.psi.ch/en/Inq/advanced-nanomanufacturing



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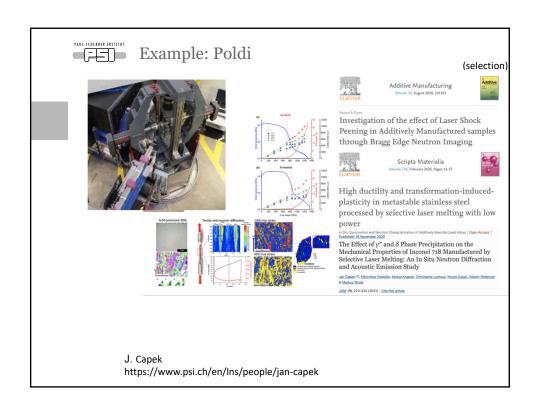
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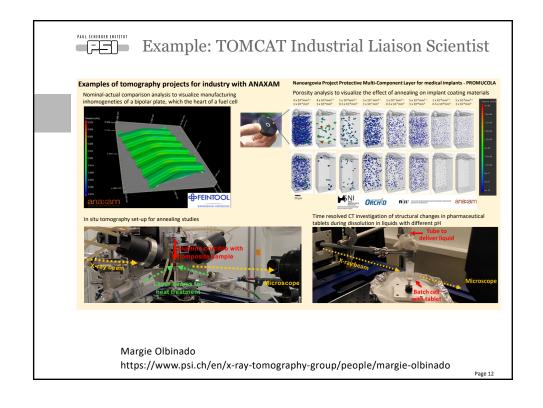
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PSI – EPFL group



SCHOOL OF ENGINEERING **MATERIALS**

Structure and Mechanics of Advanced Materials

Head: Marianne Liebi

Joint group between PSI, Photon Science Division, and EPFL, Institute of Materials

Successor of Helena van Swygenhoven

Performs research on structural and mechanical properties of diverse soft matter systems, including samples of biological origin, as well as of metals and alloys.













Steven van Petegem

https://www.psi.ch/en/smam

